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PATENT
ATTORNEY DOCKET NO. 0075/021001

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Detlef KNEBEL et al. Art Unit:
Application No.: filed concurrently Examiner:
Title: METHOD FOR LOCALLY HIGHLY RESOLVED, MASS-SPECTROSCOPIC
CHARACTERIZATION OF SURFACES USING SCANNING PROBE
TECHNOLOGY

International Application No.: PCT/DE2003/002493
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Mail Stop PCT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

PRELIMINARY AMENDMENT

Sir:

Prior to the examination and calculation of the filing fee
for this application, please amend the application as follows:

Amendments to the Claims begin on page 2 of this paper.

Remarks begin on page 6 of this paper.